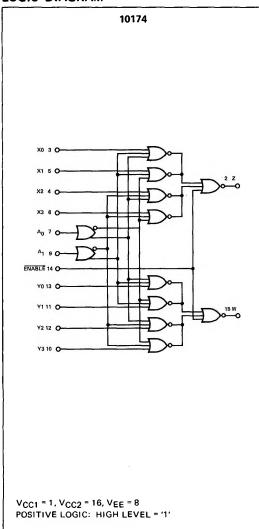
10174F: -30 to +85°C, CERDIP

## DIGITAL 10,000 SERIES ECL

#### DESCRIPTION

The 10174 is a high speed dual channel multiplexer with output enable capability. The select inputs determine one of four active data inputs for each multiplexer. An output enable forces both outputs low when in the high state. The enable is also useful in wire-ORing several multiplexers to achieve additional channel capability. Delay from data input to output is typically 3.5 nanoseconds.

#### LOGIC DIAGRAM



#### **FEATURES**

- FAST PROPAGATION DELAY
  - = 3.5 ns TYP DATA TO OUTPUT
  - = 5.0 ns TYP ADDRESS TO OUTPUT
  - = 2.0 ns TYP ENABLE TO OUTPUT
- OUTPUT ENABLE TO PERMIT OUTPUT BUSSING
- LOW POWER DISSIPATION = 290 mW/PACKAGE TYP (NO LOAD)
- HIGH FANOUT CAPABILITY CAN DRIVE TWO 50  $\Omega$  LINES
- HIGH IMMUNITY FROM POWER SUPPLY VARIA-TIONS: VEE = -5.2 V ±5% RECOMMENDED
- MEETS ECL 10,000 SERIES STANDARD INTER-**FACE SPECIFICATIONS**

#### **APPLICATIONS**

- Dual 4 to 1 Multiplexer
- Dual 4 to 1 Data Selector
- Cross Bar Switch Applications

#### TRUTH TABLE

ENABLE	ADDRES	S INPUTS	OUTPUTS				
Ē	A1	A0	Z	w			
Н	φ	φ	L	L			
L	L	L	XO	Y0			
L	L	Н	X1	Y1_			
L	H_	L	X2	Y2			
L	Н	Н	Х3	Y3			

 $<sup>\</sup>phi$  = Don't Care.

#### **TEMPERATURE RANGE**

−30 to +85°C Operating Ambient

#### **PACKAGE TYPE**

F: 16 Pin CERDIP

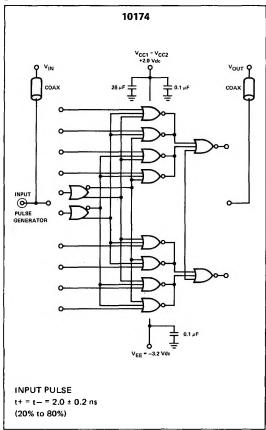
# ELECTRICAL CHARACTERISTICS (at Listed Voltages and Ambient Temperatures).

	TEST VOLTAGE VALUES												
@ Test	(Vaits)												
Temperature	V <sub>IH</sub> max	VIL min	VIHA min	VILA max	VEE								
-30°C	-0 890	-1.890	-1.205	-1.500	-5.2								
+26^C	-0.810	-1.860	-1.105	-1,475	-5.2								
+86^C	-0.700	-1.825	-1.035	-1.440	-5.2								

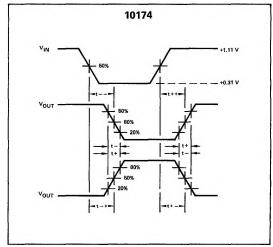
										+86 C	-0.700	-1.826	-1.036	-1.440	-5.2	1
		Pin		10174 Test Limite								TEST VOLTAGE APPLIED TO PINS LISTED BELOW:				
Characteristic	Symbol	Under tbol Test	-30°C			+25°C		+85°C			<b>├</b> ──					IVCCI
			Min	Max	Min	Тур	Mex	Min	Max	Unii	V <sub>IH max</sub>	VIL min	VIHA min	VILA max	VEE	Gnd
Power Supply Drain Current	1E	8	T -	-	-	55	73	-	-	mAd∉	-	-	-	9.0	8	1,16
Input Current Inh	linH	4		-	-	-	220		-	μAdc	4			-	8	1,16
		14	-		-	-	330	-		-	14	L <del>-</del>		-	8	1,16
	lin L	4	_	_	0.5	-	-	-	-	μAdc	-	4	-	1.00	8	1,16
Logic "1" Output Voltage	Voн	16	-1.060	0.890	-0.960	-	0.810	-0.890	-0.700	Vdc	13	-	7 - 1	-	8	1,16
Logic "0" Output Voltage	VOL	15	-1.890	-1.675	-1.850	-	-1.650	-1.825	-1.616	Vdc	14	-	_	-	8	1,16
Logic "1" Threshold Voltage	VOHA	15	-1.0B0	_	-0.980	_	T -	-0.910	_	Vdc	-		-	14	8	1,16
Logic "O" Threshold Voltage	VOLA	16	-	-1.656		_	-1.630	-	-1,596	Vdc	-		14	***	8	1,16
Switching Times*											+1,11 V		Pulse (n	Pulse Out	-3.2 V	+2.0 \
(60 Ω load)	1 1						i					1				
Propagation Delay	113+ 15+	15	-	-	- 1	3.6	-	-		ns	-	-	13	15	8	1,16
	†13– 15–	15	-	-	- '	35	-	-	-		-	-	13	1 1	1	1
	t7+ 15	15	-	-	-	5.0	-	-	-		11	-	,	!		1
	₹7- 15+	15	-	-	- 1	5.0	-	] -	-		11	-	7			1
	114+ 15-	16	-	-	-	2.0	-	-	-		-	-	14	1 1	1 1	1 L
	114 15+	15	-	-	-	2.0	-	-	-	1 1	-	-	14	1 1	1 1	1
Rise Time (20% to 80%)	1 1 1	16	-	l -	- 1	20	-	-	١ -	1	-	-	14	)	1 1	( )
Fall Time (20% to 80%)	t-	16	-	-	-	2.0	l -	-	-	' '	l –	-	14	1 '	ı '	' '

<sup>\*</sup>Unused outputs connected to a 50  $\Omega$  resistor to ground

#### SWITCHING TIME TEST CIRCUIT



### PROPAGATION DELAY WAVEFORMS @ 25°C



#### NOTES:

- 1. Each ECL 10,000 series device has been designed to meet the DC specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 fpm is mainteined. Voltage levels will shift approximately 5 mV with an air flow of 200 linear fpm. Outputs are terminated through a 50-ohm resistor to -2.0 volts.
- 2. For AC tests, all input and output cables to the scope are equal lengths of 50-ohm coaxial cable. Wire length should be <1/4 inch from  $TP_{in}$  to input pin and  $TP_{out}$  to output pin. A 50-ohm termination to ground is located in each scope channel input. Unused outputs are connected to a 50-ohm resistor to ground.
- Test procedures are shown for only one input or set of input conditions. Other inputs are tested in the same manner.
- All voltage measurements are referenced to the ground terminal.
   Terminals not specifically referenced are left electrically open.